TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC4015BP,TC4015BF,TC4015BFN

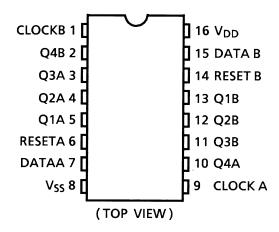
TC4015B Dual 4-Stage Static Shift Register (with serial input/parallel output)

TC4015B contains two circuits of 4 stage shift registers and the independent output is drived from each stage. As all the D type flip-flops of every stage have common RESET input, asynchronous clear operation can be achieved by an external signal at arbitrary timing. The flip-flop of each stage is triggered by rising edge of CLOCK input.

RESET input of "H" level resets the contents of all the stages to "L" regardless of CLOCK and DATA inputs and all of data outputs Q1 through Q4 become "L".

This can be used for converting serial data to palallel one and for ring counters of any numbering systems.

### **Pin Assignment**



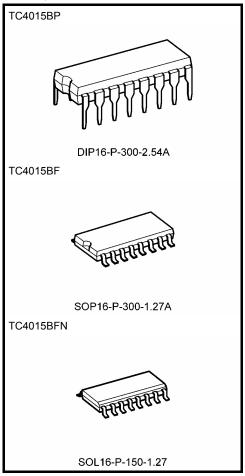
#### **Truth Table**

	Outputs						
CLOCK∆	DATA RESET		Q1	Q2	Q3	Q4	
	L	L	L	Q1	Q2	Q3	
	_ H L		Н	Q1	Q2	Q3	
$\neg$	*	L	No Change				
*	* * H		L	L	L	L	

Δ: Level change

\*: Don't care

Note: xxxFN (JEDEC SOP) is not available in Japan.



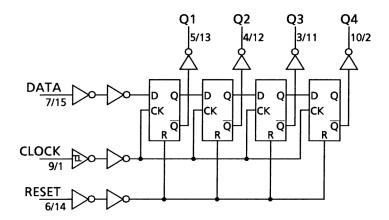
Weight

DIP16-P-300-2.54A : 1.00 g (typ.) SOP16-P-300-1.27A : 0.18 g (typ.) SOL16-P-150-1.27 : 0.13 g (typ.)

2007-10-01

### **Logic Diagram**

#### 1/2 TC4015B



### **Absolute Maximum Ratings (Note)**

Characteristics	Symbol	Rating	Unit
DC supply voltage	$V_{DD}$	V <sub>SS</sub> - 0.5~V <sub>SS</sub> + 20	V
Input voltage	V <sub>IN</sub>	V <sub>SS</sub> – 0.5~V <sub>DD</sub> + 0.5	V
Output voltage	V <sub>OUT</sub>	V <sub>SS</sub> – 0.5~V <sub>DD</sub> + 0.5	V
DC input current	I <sub>IN</sub>	±10	mA
Power dissipation	PD	300 (DIP)/180 (SOIC)	mW
Operating temperature range	T <sub>opr</sub>	-40~85	°C
Storage temperature range	T <sub>stg</sub>	-65~150	°C

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

### Operating Ranges (V<sub>SS</sub> = 0 V) (Note)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
DC supply voltage	$V_{DD}$	_	3	_	18	V
Input voltage	V <sub>IN</sub>		0	_	$V_{DD}$	V

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Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either  $V_{DD}$  or  $V_{SS}$ .



# Static Electrical Characteristics ( $V_{SS} = 0 V$ )

		Sym-	Test Condition		-40°C		25°C			85°C			
Charac	Characteristics bol			V <sub>DD</sub> (V)	Min	Max	Min	Тур.	Max	Min	Max	Unit	
High-level output voltage			$ I_{OUT}  < 1 \mu A$ $V_{IN} = V_{SS}, V_{DD}$	5	4.95	_	4.95	5.00	_	4.95	_		
		$V_{OH}$		10	9.95	_	9.95	10.00	_	9.95	_	V	
			VIN - VSS, VDD	15	14.95	_	14.95	15.00	_	14.95	_		
l			  I <sub>OUT</sub>   < 1 μA	5	_	0.05	_	0.00	0.05	_	0.05		
Low-level voltage	output	V <sub>OL</sub>	$V_{IN} = V_{SS}, V_{DD}$	10	_	0.05	_	0.00	0.05	_	0.05	V	
			VIIV - VSS, VDD	15	_	0.05	_	0.00	0.05	_	0.05		
			V <sub>OH</sub> = 4.6 V	5	-0.61	_	-0.51	-1.0	_	-0.42	_		
			V <sub>OH</sub> = 2.5 V	5	-2.50	_	-2.10	-4.0	_	-1.70	_	mA	
Output hig	h current	I <sub>OH</sub>	V <sub>OH</sub> = 9.5 V	10	-1.50	_	-1.30	-2.2	_	-1.10	_		
			V <sub>OH</sub> = 13.5 V	15	-4.00	_	-3.40	-9.0	_	-2.80	_		
			$V_{IN} = V_{SS}, V_{DD}$									<u>.                                    </u>	
		l <sub>OL</sub>	V <sub>OL</sub> = 0.4 V	5	0.61	_	0.51	1.2	_	0.42	_	mA	
Output low	v current		V <sub>OL</sub> = 0.5 V	10	1.50	_	1.30	3.2	_	1.10	_		
Output 10V	Output low current		V <sub>OL</sub> = 1.5 V	15	4.00	_	3.40	12.0	_	2.80	_		
			$V_{IN} = V_{SS}, V_{DD}$										
		V <sub>IH</sub>	V <sub>OUT</sub> = 0.5 V, 4.5 V	5	3.5	_	3.5	2.75	_	3.5	_	٧	
Input high	voltage		V <sub>OUT</sub> = 1.0 V, 9.0 V	10	7.0	_	7.0	5.50	_	7.0	_		
inputnign	voitage		V <sub>OUT</sub> = 1.5 V, 13.5 V	15	11.0	_	11.0	8.25	_	11.0	_		
			$ I_{OUT}  < 1 \mu A$										
			V <sub>OUT</sub> = 0.5 V, 4.5 V	5	_	1.5	_	2.25	1.5	_	1.5		
Input low voltage		V <sub>IL</sub>	V <sub>OUT</sub> = 1.0 V, 9.0 V	10	_	3.0	_	4.50	3.0	_	3.0	V	
			V <sub>OUT</sub> = 1.5 V, 13.5 V	15	_	4.0	_	6.75	4.0	_	4.0		
			$ I_{OUT}  < 1 \mu A$										
Input	"H" level	l <sub>IH</sub>	V <sub>IH</sub> = 18 V	18		0.1	_	10 <sup>-5</sup>	0.1	_	1.0	μА	
current	"L" level	I <sub>Ι</sub> L	V <sub>IL</sub> = 0 V	18		-0.1	_	-10 <sup>-5</sup>	-0.1	_	-1.0	μΑ	
			VIN = V00 V25	5	_	5	_	0.005	5	_	150		
Quiescent current	Quiescent supply current		$V_{IN} = V_{SS}, V_{DD}$	10	_	10	_	0.010	10	_	300	μА	
			(Note)	15		20		0.015	20		600		

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Note: All valid input combinations.



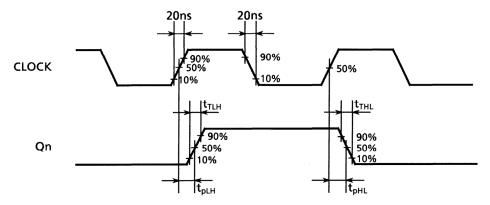
# Dynamic Electrical Characteristics (Ta = 25°C, $V_{SS}$ = 0 V, $C_L$ = 50 pF)

0		Test Condition		_			
Characteristics	Symbol		V <sub>DD</sub> (V)	Min	Тур.	Max	Unit
Output transition time			5	_	70	200	
·	t <sub>TLH</sub>	_	10	_	35	100	ns
(low to high)			15	_	30	80	
Output transition time			5	_	70	200	
Output transition time	t <sub>THL</sub>	_	10	_	35	100	ns
(high to low)			15	_	30	80	
Decreasion delevitime			5	_	130	320	
Propagation delay time	t <sub>pLH</sub>	_	10	_	60	160	ns
(CLOCK-Q)	t <sub>pHL</sub>		15	_	50	120	
B			5	_	90	400	
Propagation delay time	t <sub>pHL</sub>	_	10	_	45	200	ns
(RESET-Q)			15	_	40	160	
			5	3.0	8	_	
Max clock frequency	f <sub>CL</sub>	_	10	6.0	17	_	MHz
			15	8.5	20	_	
			5	_	35	180	
Min clock pulse width	t₩	_	10	_	25	80	ns
			15	_	20	50	
			5	_	50	200	
Min pulse width	twH	_	10	_	25	80	ns
(RESET)			15	_	20	60	
			5	_	8	70	
Min set-up time	tsu	_	10	_	4	40	ns
(DATA-CLOCK)			15	_	0	30	
			5	_	6	60	
Min hold time	tH	_	10	_	5	30	ns
(DATA-CLOCK)			15	_	4	20	
			5	_	0	80	
Min removal time	t <sub>rem</sub>	_	10	_	0	30	ns
(RESET-CLOCK)			15	_	0	20	
			5			I.	
Max clock input rise time	trCL	_	10	No limit			μS
Max clock input fall time	tfCL		15				
Input capacitance	C <sub>IN</sub>	_	1	_	5	7.5	pF

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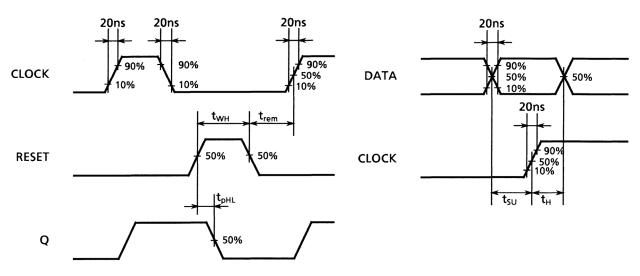
### **Waveforms for Measurement of Dynamic Characteristics**

### Waveform 1



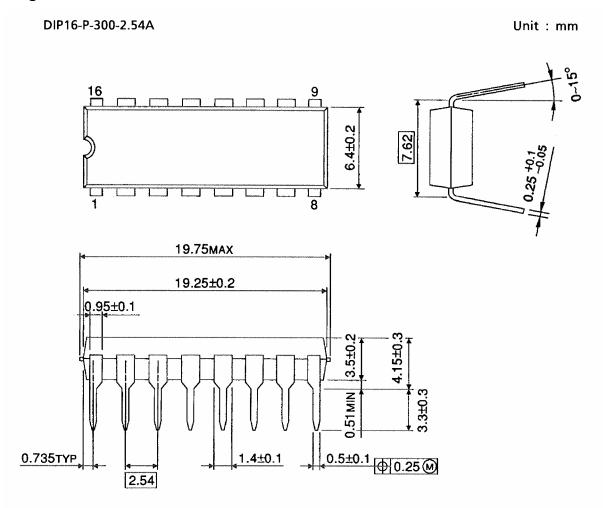
### Waveform 2

### Waveform 3



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### **Package Dimensions**

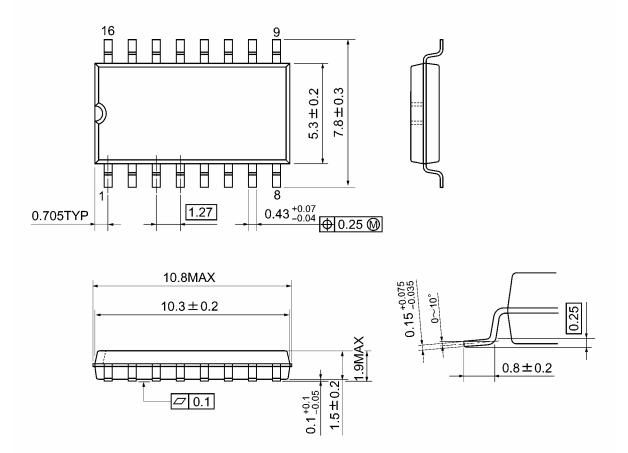


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Weight: 1.00 g (typ.)

### **Package Dimensions**

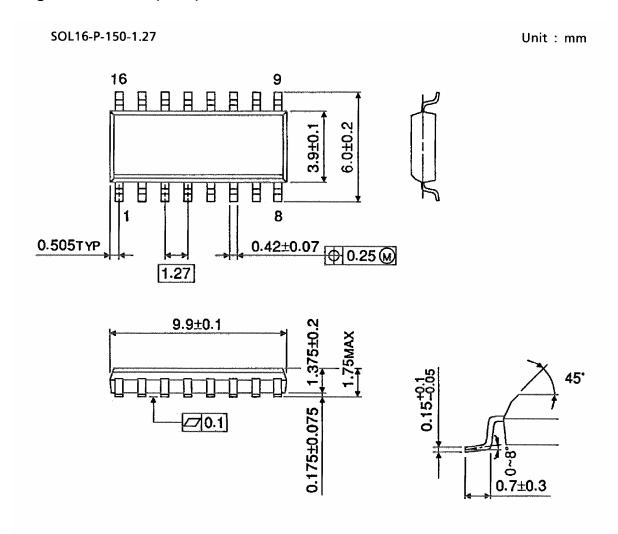
SOP16-P-300-1.27A Unit: mm



Weight: 0.18 g (typ.)



### **Package Dimensions (Note)**



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Note: This package is not available in Japan.

Weight: 0.13 g (typ.)

### **RESTRICTIONS ON PRODUCT USE**

20070701-EN GENERAL

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